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190		ļ.,,	Tec	chnolo	ogy N	fleet	ing,	pages 18	<u>1-1</u>	84, September 29 - Octobe	r 1, 2002	2.				
,			Haigang Feng, et al,. "An ESD Protection Circuit for Mixed-Signal ICs," IEEE 2001 Custom Integrated Circuits Conference, pages 493-496, May 6-9, 2001.													
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14/1	 		Electronics Letters, Vol. 38, No. 11, pages 511-513, May 23, 2002. Guang Chen et al., "A Systematic Study of ESD Protection Structures for RF ICs," 2003 IEEE													
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